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<b>Substitute for form 1449A/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/020,894
				Filing Date	December 19, 2001
				First Named Inventor	Jeong Ki Park et al.
				Art Unit	2871
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	8733.556.00

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
PE	AA	5,914,762	06-22-1999	Lee et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)				
PE	BA	JP-11-125836	05-11-1999	Lee Seung Hee et al.		
PE	BB	JP-09-211495	08-15-1997	Hirakata Yoshiharu et al.		

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See attached Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

Examiner Signature	<i>SMH</i> <i>FAM</i> <i>CRD</i>	Date Considered	02/12/03
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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached

DC:112763.1

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEAttorney Docket No.  
8733.556.00Application No.  
TBAJ1011 U.S. PTO  
10/020894  
12/19/01LIST OF REFERENCES CITED BY  
APPLICANT

(Use Several Sheets if Necessary)

Date: December 19, 2001

Applicant  
Jeong-Ki PARK et al.Filing Date  
December 19, 2001Group  
TBA

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EXAMINER INITIAL *	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PS	5,598,285	1/1997	Kondo et al.	349	39	September 20, 1993
PS	5,838,037	11/1998	Masutani et al.	257	296	May 19, 1997
PS	5,946,060	8/1999	Nishiki et al.	349	48	June 3, 1997
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PS	6,028,653	2/2000	Nishida	349	141	June 19, 1997
PS	6,097,454	8/2000	Zhang et al.	349	43	June 29, 1999

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DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION
			YES NO
PS 09-005764	1/1997	Japan	Abstract
PS 09-073101	3/1997	Japan	Abstract
PS 09-105908	4/1997	Japan	Abstract
PS 09-101538	4/1997	Japan	Abstract

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PS	R. Kieler et al.; "In-Plane Switching of Nematic Liquid Crystals"; Japan Display '92; pages 547-550
PS	M. Oh-e, et al.; "Principles and Characteristics of Electro-Optical Behaviour with In-Plane Switching Mode"; Asia Display '95; pages 577-580
PS	M. Ohta et al.; "Development of Super-TFT-LCDs with In-Plane Switching Display Mode"; Asia Display '95; pages 707-710
PS	S. Matsumoto et al.; "Display Characteristics of In-Plane Switching (IPS) LCDs and a Wide-Viewing-Angle 14.5-in. OPS TFT-LCD; Euro Display '96; pages 445-448
PS	H. Wakemoto et al.; "An Advanced In-Plane Switching Mode TFT-LCD"; SID 97 Digest; pages 929-932
PS	S.H. Lee et al.; "High-Transmittance, Wide-Viewing-Angle Nematic Liquid Crystal Display Controlled by Fringe-Field Switching; Asia Display '98; pages 371-374

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